

PCN Number:	20230327003.1	PCN Date:	March 30, 2023
Title:	Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, and additional Assembly & BOM options for select devices		
Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	Jun 27, 2023	Sample requests accepted until:	Apr 29, 2023*

***Sample requests received after April 29, 2023 will not be supported.**

Change Type:

<input checked="" type="checkbox"/>	Assembly Site	<input checked="" type="checkbox"/>	Assembly Process	<input checked="" type="checkbox"/>	Assembly Materials
<input checked="" type="checkbox"/>	Design	<input checked="" type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input checked="" type="checkbox"/>	Wafer Fab Site	<input checked="" type="checkbox"/>	Wafer Fab Materials	<input checked="" type="checkbox"/>	Wafer Fab Process
		<input type="checkbox"/>	Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC9) and Assembly & BOM option for selected devices as listed below in the product affected section. Construction differences are noted below:

Current Fab Site			Additional Fab Site		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
SFAB	HCMOS	150 mm	RFAB	LBC9	300 mm

The die was also changed as a result of the process change.

Additionally, there will be a BOM/Assembly options introduced for these devices:

Group 1 Device list (RFAB/Process migration & TFME as new Assembly and BOM options– PW packaged devices)

	MLA (Current)	MLA (New)	TFME
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil
Lead finish	NiPdAu	NiPdAu	Matte Sn
Mount Compound	4147858	4147858	SID#A-03
Mold Compound	4211471	4211471	SID#R-31

Group 2 Device list (RFAB/Process migration & HFTF as new Assembly and BOM options – D Packaged Device)

	MLA (Current)	MLA (New)	HFTF
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil
Lead finish	NiPdAu	NiPdAu	Matte Sn
Mount Compound	4147858	4147858	SID#R-03
Mold Compound	4211880	4211880	SID#R-30

Group 3 Device list (RFAB/Process migration & BOM Option – PW, NS, DW & DB)

packaged devices)

	MLA Current	MLA New
Bond wire diameter (Cu)	0.96 mil	0.8 mil

Group 4 Device list (RFAB/Process migration & FMX as new Assembly and BOM options – D packaged devices)

	MLA (Current)	MLA (New)	FMX
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil

Group 5 Device list (RFAB/Process migration & MLA as new Assembly and BOM options – D packaged devices)

	ASESH	FMX Current	FMX (New)	MLA (New)
Bond wire diameter (Cu)	0.8 mil	0.96 mil	0.8mil	0.8 mil
Lead finish	Matte Sn	NiPdAu	NiPdAu	NiPdAu
Mount Compound	SID#EY1000063	4147858	4147858	4147858
Mold Compound	SID#EN2000506	4211880	4211880	4211880

Upon expiry of this PCN TI will combine lead free solutions in a single [standard part number](#), for the devices in groups 1 & 2. For example; [SN74LV10APWR](#) – can ship with both Matte Sn and NiPdAu/Ag.

Example:

- Customer order for 7500 units of SN74LV10APWR with 2500 units SPQ (Standard Pack Quantity per Reel).
- TI can satisfy the above order in one of the following ways.
 - I. 3 Reels of NiPdAu finish.
 - II. 3 Reels of Matte Sn finish
 - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
 - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

Additionally, as a result of these changes, some of the impacted device datasheets will be updated. Target for these datasheet updates is the start of production. For a preview of these upcoming datasheet changes, please see below:

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150- millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change	<input checked="" type="checkbox"/> No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
RFAB	RFB	USA	Richardson

Die Rev:

Current

New

Die Rev [2P]	Die Rev [2P]
H, I, M	A

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
MLA	MLA	MYS	Kuala Lumpur
ASESH	ASH	CHN	Shanghai
FMX	MEX	MEX	Aguascalientes
HFTFAT	HFT	CHN	Hefei
TFME	NFM	CHN	Economic Development Zone

Sample product shipping label (not actual product label)



TEXAS INSTRUMENTS
MADE IN: Malaysia
2DC: 20:

MSL 2 / 260C/1 YEAR	SEAL DT
MSL 1 / 235C/UNLIM	03/29/04

OPT:
ITEM: 39
LBL: 5A (L)T0:1750




(1P) **SN74LS07NSR**
 (Q) **2000** (D) **0336**
 (31T) LOT: 3959047MLA
 (4W) TKY (1T) 7523483SI2
 (P)
 (2P) REV: (V) 0033317
 (20L) ~~SGO: SHE~~ (21L) ~~CCO: USA~~
 (22L) ~~ASO: MLA~~ (23L) ~~ACO: MYS~~

Product Affected:**Group 1 Device list (RFAB/Process migration & TFME as new Assembly and BOM options– PW packaged devices)**

SN74LV05APWR	SN74LV10APWR	SN74LV174APWR	SN74LV367APWR
SN74LV06APWR	SN74LV166APWR	SN74LV175APWR	SN74LV393APWR

Group 2 Device list (RFAB/Process migration & HFTF as new Assembly and BOM options – D Packaged Device)

SN74LV06ADR

Group 3 Device list (RFAB/Process migration & BOM Option – PW, NS, DW & DB packaged devices)

SN74LV06ANSR	SN74LV244ADWRG4	SN74LV374ADWR	SN74LV541APWR
SN74LV244ADBR	SN74LV273ADBR	SN74LV540APWR	SN74LV541APWRG4
SN74LV244ADBRE4	SN74LV273ADBRE4	SN74LV541ADBR	SN74LV573APWR
SN74LV244ADBRG4	SN74LV273ADBRG4	SN74LV541ADBRE4	SN74LV573APWRG4
SN74LV244ADWR	SN74LV273ADWR	SN74LV541ADWR	

Group 4 Device list (RFAB/Process migration & FMX as new Assembly and BOM options– D packaged devices)

SN74LV164ADR	SN74LV393ADR
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Group 5 Device list (RFAB/Process migration & MLA as new Assembly and BOM options – D packaged devices)

SN74LV138ADR	SN74LV165ADR	SN74LV174ADR	SN74LV595ADR
SN74LV157ADR	SN74LV165ADRG4	SN74LV367ADR	

For alternate parts with similar or improved performance, please visit the product page on TI.com

Qualification Report
Approve Date 15-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV573APWR	Qual Device: SN74LV540APWR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQRKSRQ1	QBS Reference: SN74LV240APWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	1/77/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/77
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	1/45/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV573APWR is qualified at MSL1 260C
- Qual Device SN74LV540APWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-016

Qualification Report
Approve Date 16-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV244ADWR	Qual Device: SN74LV273ADWR	Qual Device: SN74LV374ADWR	Qual Device: SN74LV541ADWR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV240APWR	QBS Reference: SN74LV374APWR	QBS Referen SN74LV574AP
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/770	1/770	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	3/2310	1/770	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/770	1/770	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	1/450	1/450	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	1/770	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/770	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	1/3/0	1/3/0	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	-	-	-	-	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	1/3/0	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	1/6/0	1/6/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	-	-	1/300	1/300	1/300
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	3/900	3/900	-	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV244ADWR is qualified at MSL1 260C
- Qual Device SN74LV273ADWR is qualified at MSL1 260C
- Qual Device SN74LV374ADWR is qualified at MSL1 260C
- Qual Device SN74LV541ADWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-017

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV244ADDR	Qual Device: SN74LV273ADDR	Qual Device: SN74LV541ADDR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: TL4941DR	QBS Reference: TLC320AD77CDBR	QBS Reference: SN74LV244AQRKSRQ1	QBS Reference: SN74LV273AQRKSRQ1	QBS Reference: SN74LV541AQRKSRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	1/77/0	-	-	1/77/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	1/77/0	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	-	-	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/231/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	1/45/0	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	1/77/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	-	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	1/10/0	1/10/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	-	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	-	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-	-	-	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot and cold	-	-	-	-	3/50/0	-	-	3/50/0	1/30/0	1/30/0

- QBS: Qual By Similarity
- Qual Device SN74LV244ADDR is qualified at MSL1 260C



- Qual Device SN74LV273ADDR is qualified at MSL1 260C
- Qual Device SN74LV541ADDR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-018

Qualification Report
Approve Date 15-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV541APWR	Qual Device: SN74LV541APWRG4	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV240APWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	1/77/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	1/45/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-

CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV541APWR is qualified at MSL1 260C
- Qual Device SN74LV541APWRG4 is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-003

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV175APWR	Qual Device: SN74LV166APWR	Qual Device: SN74LV174APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR	QBS Reference: SN74LV138APWR	QBS Reference: SN74LV595AOWBQBRO1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	3/231/0	1/77	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	3/2400/0	-	-	-

SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	-	-	3/66/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	-	-	-	3/66/0	-	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	3/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	3/9/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	3/90/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV175APWR is qualified at MSL1 260C
- Qual Device SN74LV166APWR is qualified at MSL1 260C
- Qual Device SN74LV174APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-036

TI Information
Selective Disclosure

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV393APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-

HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	3/66/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	-	3/66/0	-	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	3/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	3/9/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	3/90/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV393APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-037

Qualification Report
Approve Date 20-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV166APWR	Qual Device: SN74LV174APWR	Qual Device: SN74LV175APWR	QBS Reference: TMUX1308QPWRQ1	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	3/231/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	3/231/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	3/231/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	3/231/0	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	3/2400/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	3/30/0	-
ESD	E2	ESD CDM	-	2000 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	5000 Volts	-	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV166APWR is qualified at MSL1 260C
- Qual Device SN74LV174APWR is qualified at MSL1 260C
- Qual Device SN74LV175APWR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-038

Qualification Report
Approve Date 21-SEPTEMBER-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV4T125PWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	1/77/0	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	3/30/0	3/15/0
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	1/3/0	3/9/0
ESD	E2	ESD HBM	-	4000 Volts	-	1/3/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV00APWR is qualified at MSL1 260C
- Qual Device SN74LV04APWR is qualified at MSL1 260C
- Qual Device SN74LV02APWR is qualified at MSL1 260C
- Qual Device SN74LV05APWR is qualified at MSL1 260C
- Qual Device SN74LV06APWR is qualified at MSL1 260C
- Qual Device SN74LV07APWR is qualified at MSL1 260C
- Qual Device SN74LV07APWRG3 is qualified at MSL1 260C
- Qual Device SN74LV08APWR is qualified at MSL1 260C
- Qual Device SN74LV10APWR is qualified at MSL1 260C
- Qual Device SN74LV11APWR is qualified at MSL1 260C
- Qual Device SN74LV125APWR is qualified at MSL1 260C
- Qual Device SN74LV126APWR is qualified at MSL1 260C
- Qual Device SN74LV132APWR is qualified at MSL1 260C
- Qual Device SN74LV14APWR is qualified at MSL1 260C
- Qual Device SN74LV20APWR is qualified at MSL1 260C
- Qual Device SN74LV21APWR is qualified at MSL1 260C
- Qual Device SN74LV27APWR is qualified at MSL1 260C
- Qual Device SN74LV32APWR is qualified at MSL1 260C
- Qual Device SN74LV74APWR is qualified at MSL1 260C
- Qual Device SN74LV86APWR is qualified at MSL1 260C
- Qual Device SN74LV4T125PWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2111-095

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164ADR	Qual Device: SN74LV393ADR	OBS Reference: SN74HCS74QPWRQ1	OBS Reference: SN74HCS74QDRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV164ADR	QBS Reference: SN74LV393ADR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	3/231/0	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	3/45/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	3/45/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	3/30/0	-	-	-	-

ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	1/3/0	1/3/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0	1/30/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164ADR is qualified at MSL1 260C
- Qual Device SN74LV393ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-012

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164APWR	Qual Device: SN74LV393APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-

SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164APWR is qualified at MSL1 260C
- Qual Device SN74LV393APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-016

Qualification Report
Approve Date 17-March-2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138ADR	Qual Device: SN74LV157ADR	Qual Device: SN74LV165ADR	Qual Device: SN74LV165ADR04	Qual Device: SN74LV174ADR	Qual Device: SN74LV193ADR	Qual Device: SN74LV367ADR	Qual Device: SN74LV395ADR	QBS Reference: SN74HC274CQDR04	QBS Reference: SN74HC274CQDR04	QBS Reference: SN74LV138ADR	QBS Reference: SN74LV157ADR	QBS Reference: SN74LV165ADR	QBS Reference: SN74LV165ADR04
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAFT	A3	Autoclave	121C/1Sp9g	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAFT	A3	Autoclave	121C/1Sp9g	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
UHAFT	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1450
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
SD	C3	PB Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
PD	C4	Physical Dimensions	Cpin-1.67	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
ESD	E2	ESD CDM	-	250 Volt	-	-	-	-	-	-	-	-	-	-	-	-	-	-
ESD	E2	ESD CDM	-	500 Volt	-	-	-	-	-	-	-	-	-	-	-	-	-	130
ESD	E2	ESD HBM	-	2000 Volt	-	-	-	-	-	-	-	-	-	-	-	-	-	130
LU	E4	Latch-Up	Per JEDEC78	-	-	-	-	-	-	-	-	-	-	-	-	-	-	150
CHAR	F5	Electrical Characterization	Per Datasheet Parameters	-	1300	1300	1300	1300	1300	1300	1300	-	-	-	1300	1300	1300	-
CHAR	F5	Electrical Distributions	Cpin-1.67 Room, hot and cold	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3900

- QBS: Qual By Similarity
- Qual Device SN74LV138ADR is qualified at MSL1 260C
- Qual Device SN74LV157ADR is qualified at MSL1 260C
- Qual Device SN74LV165ADR is qualified at MSL1 260C
- Qual Device SN74LV165ADR04 is qualified at MSL1 260C
- Qual Device SN74LV174ADR is qualified at MSL1 260C
- Qual Device SN74LV193ADR is qualified at MSL1 260C
- Qual Device SN74LV367ADR is qualified at MSL1 260C
- Qual Device SN74LV395ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temperature Cycle options per JEDEC47: -65C/150C/700 Cycles and -65C/150C/500 Cycles

Qualify and Environmental data is available at TI's external Web site: <http://www.ti.com>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

TI Qualification ID: R-AMPD-2112-020

Qualification Report
Approve Date 16-NOVEMBER -2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138ADR	Qual Device: SN74LV157ADR	Qual Device: SN74LV165ADR	Qual Device: SN74LV165ADR04	Qual Device: SN74LV174ADR	Qual Device: SN74LV193ADR	Qual Device: SN74LV367ADR	Qual Device: SN74LV395ADR	QBS Reference: SN74HC274CQDR04	QBS Reference: SN74HC274CQDR04	QBS Reference: SN74LV138ADR	QBS Reference: SN74LV157ADR	QBS Reference: SN74LV165ADR	QBS Reference: SN74LV165ADR04
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAFT	A3	Autoclave	121C/1Sp9g	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAFT	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
UHAFT	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77	-	-	-	-	-	-	-	-	-	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1450
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	1770
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	-	-	-	-	-	-	-
SD	C3	PB Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
SD	C3	PB Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes); PB Solder	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3660
SD	C3	PB-Free Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w/150C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3660
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
PD	C4	Physical Dimensions	Cpin-1.67	-	-	-	-	-	-	-	-	-	-	-	-	-	-	3900
ESD	E2	ESD CDM	-	250 Volt	1/30	-	-	-	-	-	-	-	-	-	-	-	-	-
ESD	E2	ESD CDM	-	500 Volt	-	-	-	-	-	-	-	-	-	-	-	-	-	130

ESD	E2	ESD HBM	-	1000 Volt	-	-	-	-	-	-	-	-	190	-	-	-	-		
ESD	E2	ESD HBM	-	2000 Volt	-	-	-	-	-	-	-	-	-	-	190	-	190		
LU	E4	Latch-Up	Per JEDEC78	-	-	-	-	-	-	-	-	-	190	-	-	-	-		
LU	E4	Latch-Up	Per JEDEC78	-	-	-	-	-	-	-	-	-	-	-	160	-	160		
CHAR	E5	Electrical Characterization	Per DataSheet Parameters	-	1900	1900	1900	1900	1900	1900	1900	1900	1900	1900	1900	1900	3900	-	
CHAR	E5	Electrical Distributions	Cpi-1.57 Room, hot, and cold	-	-	-	-	-	-	-	-	-	-	-	-	-	3900	-	3900

- QBS: Qual By Similarity
- Qual Device SN74LV139APWR is qualified at MSLL 260C
- Qual Device SN74LV139APWR is qualified at MSLL 260C
- Qual Device SN74LV137APWR is qualified at MSLL 260C
- Qual Device SN74LV164APWR is qualified at MSLL 260C
- Qual Device SN74LV164APWR is qualified at MSLL 260C
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- Qual Device SN74LV164APWR is qualified at MSLL 260C
- Qual Device SN74LV164APWR is qualified at MSLL 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/BIAS HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 160C/300 Hours, and 185C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 180C/1k Hours, and 270C/420 Hours
- The following are equivalent Temp Cycle options per JEDEC78: -85C/185C/700 Cycles and -85C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

TI Qualification ID: RA-IPD-2112-024

TI Information
Selective Disclosure

Qualification Report

Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164ADR	Qual Device: SN74LV393ADR	QBS Reference: LM2904BQDRQ1	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQQBQBRQ1
HAST	A2	Biased HAST	130C	96 Hours	-	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-
UHAST	A3	Unbiased HAST	130C	192 Hours	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	1/45/0

HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	1/77/0
HTOL	B1	Life Test	150C	408 Hours	-	-	3/231/0	-	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/4 ^{1,2}	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	1/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	3/9/0	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	3/18/0	1/6/0	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164ADR is qualified at MSL1 260C
- Qual Device SN74LV393ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-059

- [1]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.
[2]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138ADR	Qual Device: SN74LV157ADR	Qual Device: SN74LV155ADR	Qual Device: SN74LV174ADR	Qual Device: SN74LV367ADR	Qual Device: SN74LV595ADR	Qual Device: SN74LV155ADR04	QBS Reference: LMC9048QDRQ1	QBS Reference: SN74HC374QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV164ADR	QBS Reference: SN74LV393ADR	QBS Reference: SN74LV595AQWQ1
HAST	A2	Biased HAST	130C	96 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1770
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
UHAST	A3	Unbiased HAST	130C	192 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	-	-	-	-	-	-	30310	-	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	30310	-	-	-	-	1770
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	30380	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	30350	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1450
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1770
HTOL	B1	Life Test	150C	408 Hours	-	-	-	-	-	-	-	30310	-	-	-	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	304004 ^{1,2}	304000	-	-	-	-
SD	C3	PB Solderability	Precondition w/155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1150	1150	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w/155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1150	1150	-	-	-	-
PD	C4	Physical Dimensions	Cpk>=1.67	-	-	-	-	-	-	-	-	3900	3900	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/30	-	-	-	1/30	1/30	-	-	-	1/30	1/30	1/30	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	-	1/30	-	-	-	1/30
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	390	1/30	-	-	-	1/30
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	3180	160	-	-	-	160
CHAR	E5	Electrical Characterization	Per DataSheet Parameters	-	1/300	1/300	1/300	1/300	1/300	1/300	1/300	-	-	1/300	1/300	1/300	-
CHAR	E5	Electrical Distributions	Cpk>=1.67 Room, hot, and cold	-	-	-	-	-	-	-	-	3900	3900	-	-	-	3900

- QBS: Qual By Similarity
- Qual Device SN74LV138ADR is qualified at MSL1 260C
- Qual Device SN74LV157ADR is qualified at MSL1 260C
- Qual Device SN74LV155ADR is qualified at MSL1 260C
- Qual Device SN74LV174ADR is qualified at MSL1 260C
- Qual Device SN74LV367ADR is qualified at MSL1 260C
- Qual Device SN74LV595ADR is qualified at MSL1 260C
- Qual Device SN74LV155ADR04 is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THBiased HAST, Temperature Cycle, Thermal Shock, and HTSL as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/2k Hours, 140C/480 Hours, 150C/300 Hours, and 165C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/2k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -65C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-AMPD-2112-060

[1] Precon and ELFR fails due to a defect screenable at production test. SD available upon request.
[2] Precon and ELFR fails due to a defect screenable at production test. SD available upon request.

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06APWR	Qual Device: SN74LV05APWR	Qual Device: SN74LV10APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	3/2400/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV06APWR is qualified at MSL1 260C
- Qual Device SN74LV05APWR is qualified at MSL1 260C
- Qual Device SN74LV10APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycle

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-044

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ADR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: OPA4991QDRQ1	QBS Reference: SN74LV14ADR	QBS Reference: SN74LV21ADR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	1/77/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	2/154/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-	-
HTOL	B1	Life Test	150C	408 Hours	-	-	-	1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	4000 Volts	-	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	1/6/0	1/6/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	1/30/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	3/90/0	3/90/0	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-046

TI Information
Selective Disclosure

Qualification Report Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ADR	QBS Reference: SN74HCS174DR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: SN74LV21ADR
HAST	A2	Biased HAST	130C	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	1/77/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-
UHAST	A3	Unbiased HAST	130C	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	-

HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	1/45/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	3/66/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	3/66/0	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	-	3/9/0	-	-	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-
CHAR	E5	Electrical Characterization	Min, Typ, Max Temp	-	1/30/0	3/90/0	-	-	1/30/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-047

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ANSR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: SN74LV14ANSR	QBS Reference: SN74LVC8T245NSR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	1/76/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	1/76/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	1/6/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	3/90/0	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ANSR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-048

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Location	E-Mail
WW Change Management Team	PCN_ww_admin_team@list.ti.com

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